United States Patent [19]

Kitada et al.

[11] **Des. 254,778**

[45] ** **Apr. 22, 1980**

---

[54] **ULTRASONIC WAVE THICKNESS METER**

[75] Inventors: **Toyohiko Kitada**, Sagamihara; **Kunio Iiyama; Kazuyuki Ito**, both of Yokohama; **Minoru Tamura**, Chigasaki; **Takanori Arioka**, Tokyo, all of Japan

[73] Assignee: **Tokyo Keiki Company Limited**, Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **867,172**

[22] Filed: **Jan. 5, 1978**

[30] **Foreign Application Priority Data**

Jul. 7, 1977 [JP] Japan 52-26412

[51] **Int. Cl.** .... **D10—04**

[52] **U.S. Cl.** **D10/46**; D10/78

[58] **Field of Search** .... D10/46, 75, 78, 47; 73/597, 431, 432 R

[56] **References Cited**

U.S. PATENT DOCUMENTS

D. 189,849	3/1961	Koch	D10/46
D. 213,962	4/1969	Potruch	D10/78
D. 246,956	1/1978	Perry	D10/78
D. 248,734	8/1978	Husseri	D10/46

OTHER PUBLICATIONS

Krautkramer-Brochure-2/76-D-Meter Wall Thickness Gauge.

Metrifast-Flyer-5/24/77-Metal Detector.

Product Engineering-10/78-p. 106-Thickness Gauge at top left.

Primary Examiner—Nelson C. Holtje

Attorney, Agent, or Firm—Haseltine, Lake & Waters

[57] **CLAIM**

The ornamental design for an ultrasonic wave thickness meter, as shown and described.

DESCRIPTION

FIG. **1** is a front elevational view of an ultrasonic wave thickness meter showing our new design;

FIG. **2** is a rear elevational view thereof;

FIG. **3** is a right side elevational view thereof;

FIG. **4** is a left side elevational view thereof;

FIG. **5** is a top plan view thereof; and

FIG. **6** is a bottom plan view thereof.

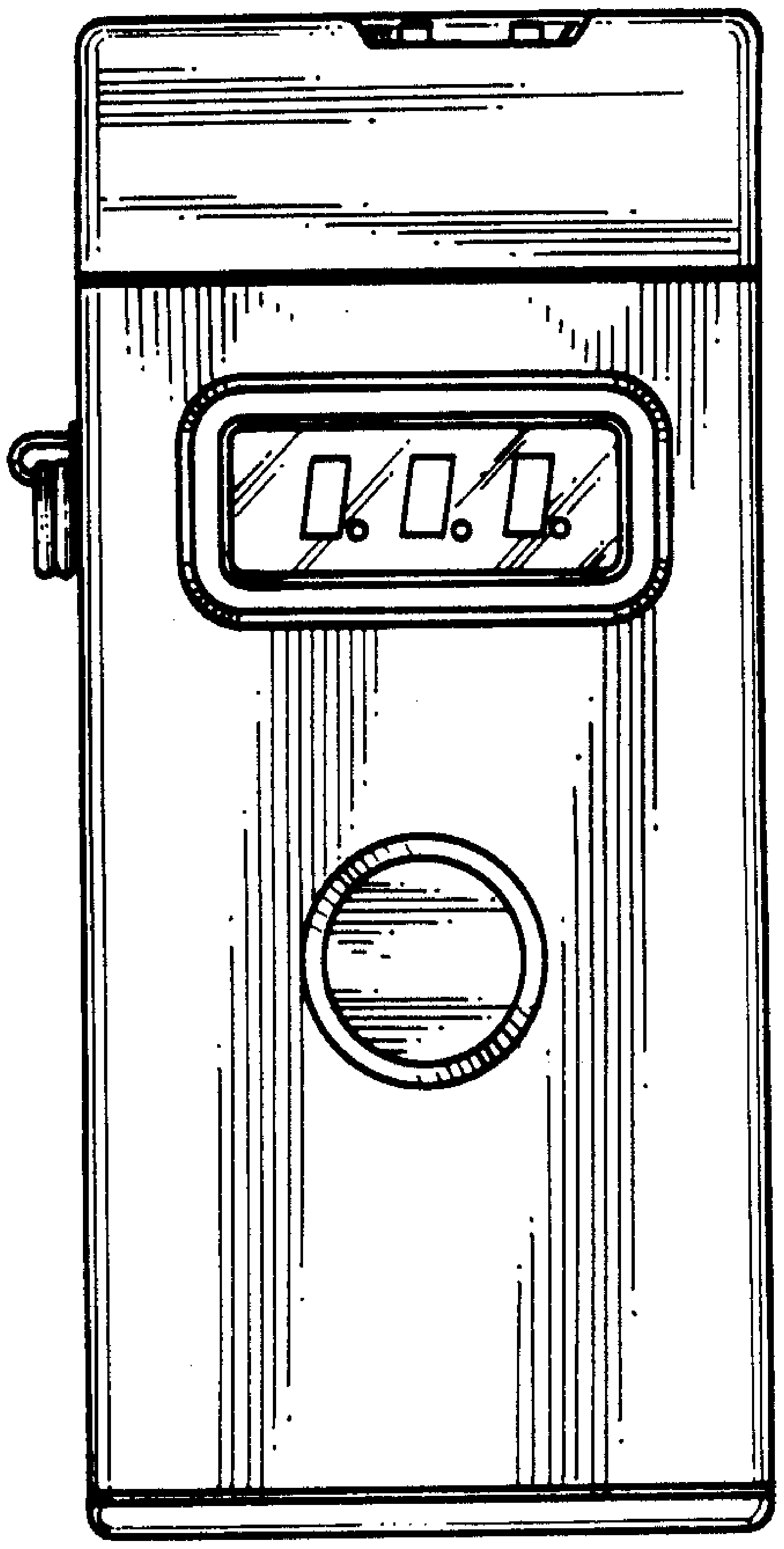

FIG. 1

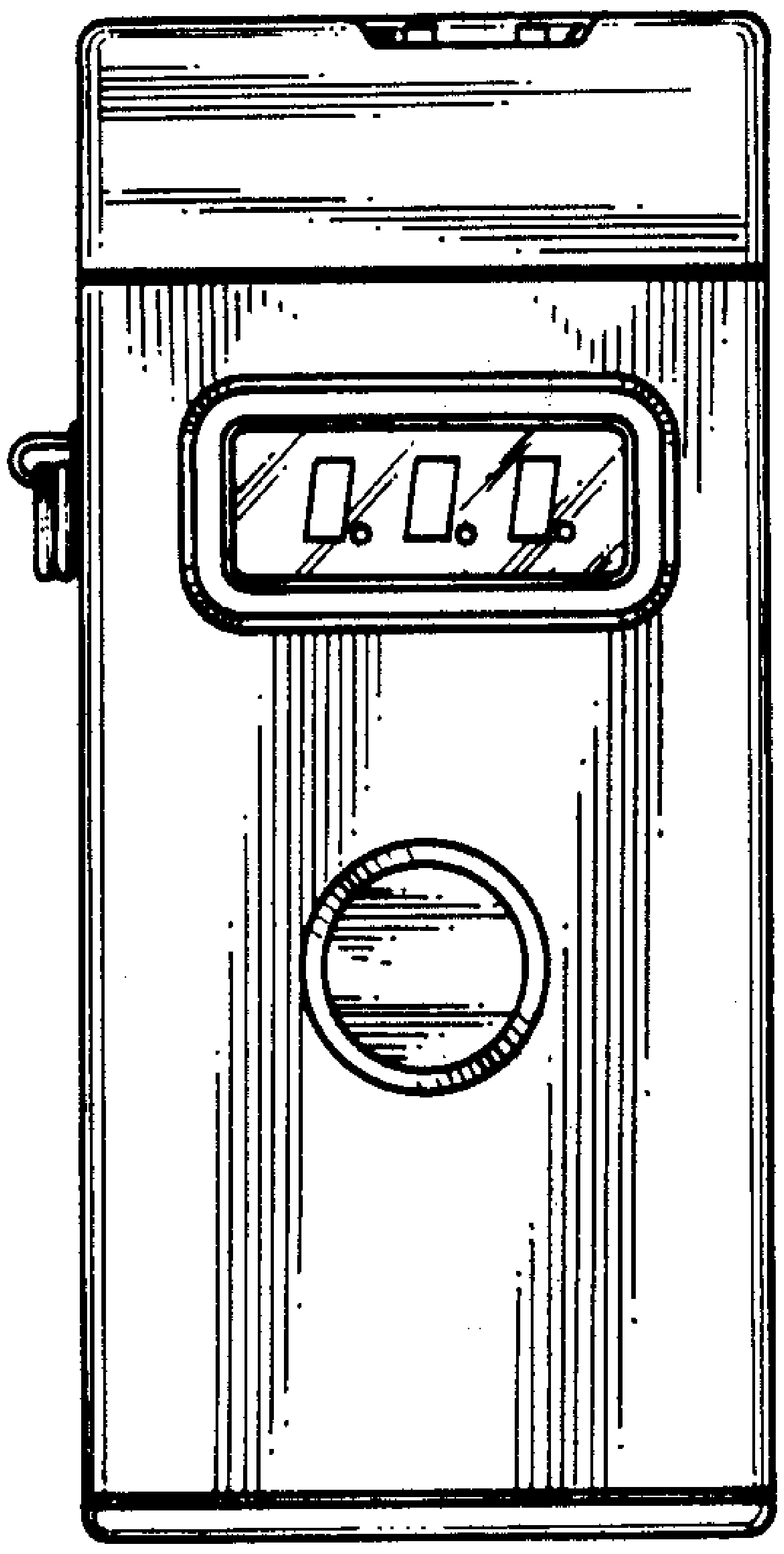

FIG. 2

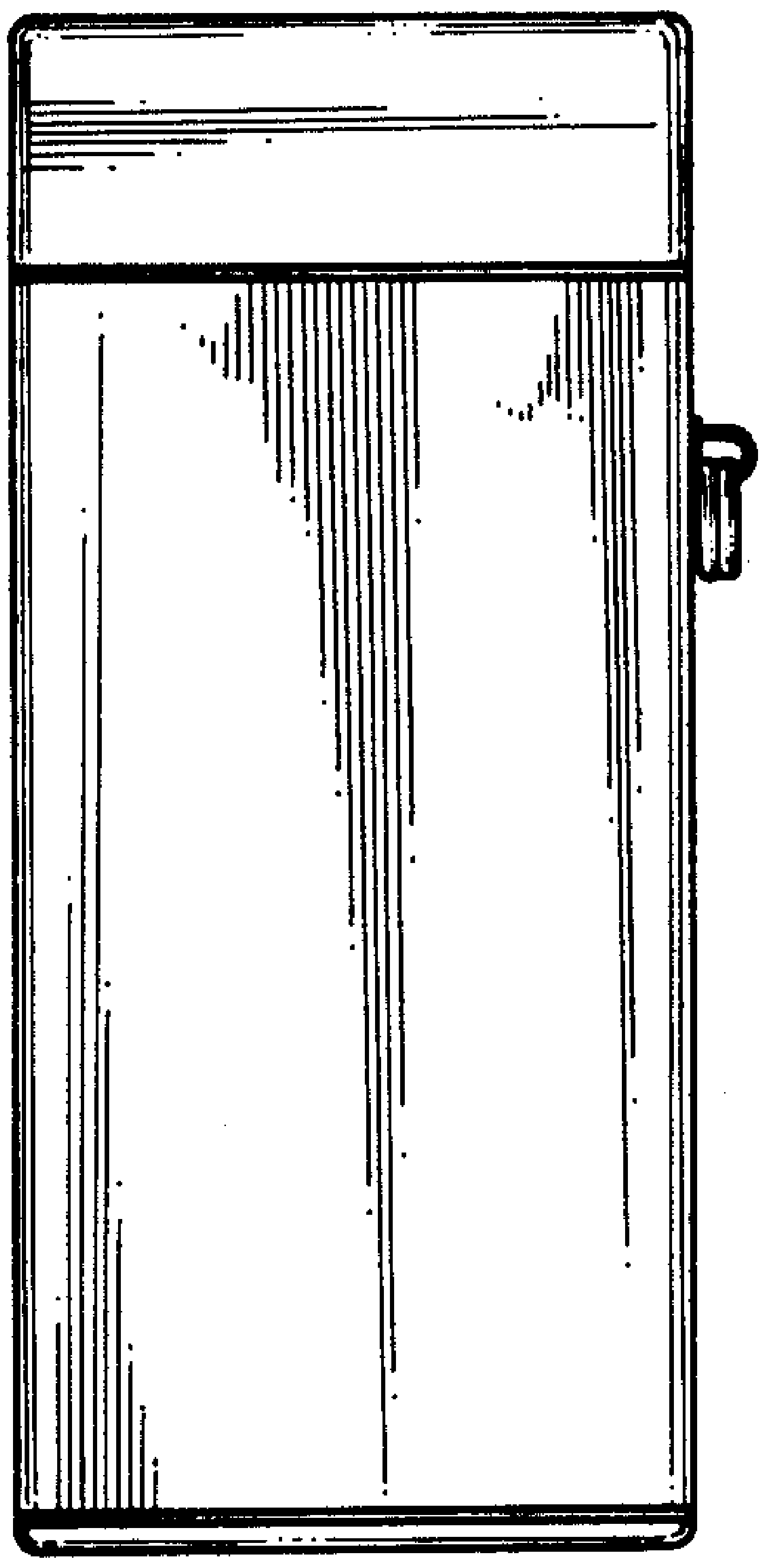

FIG. 3

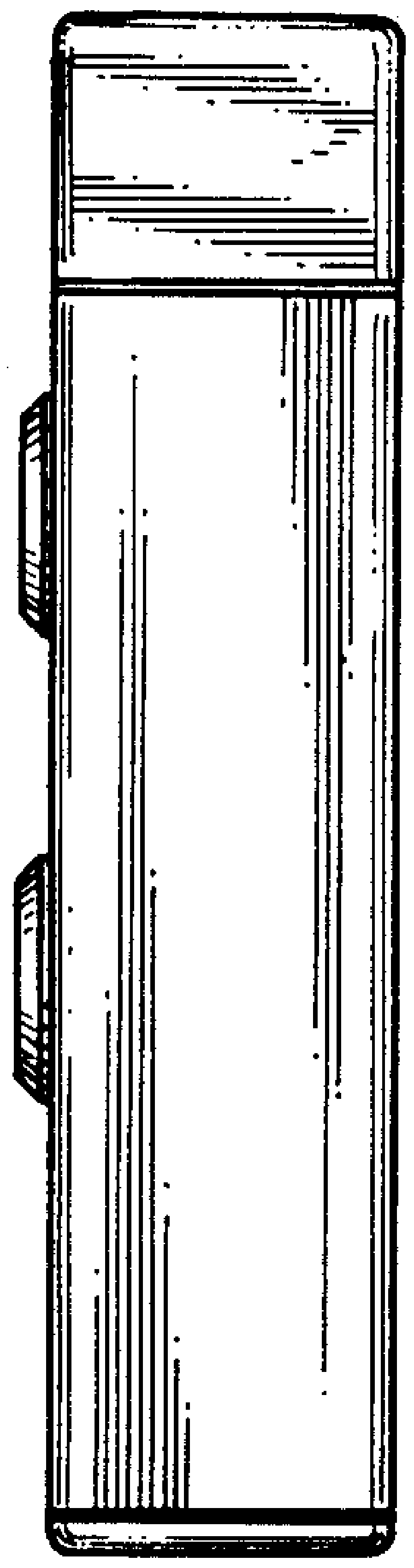

FIG. 4

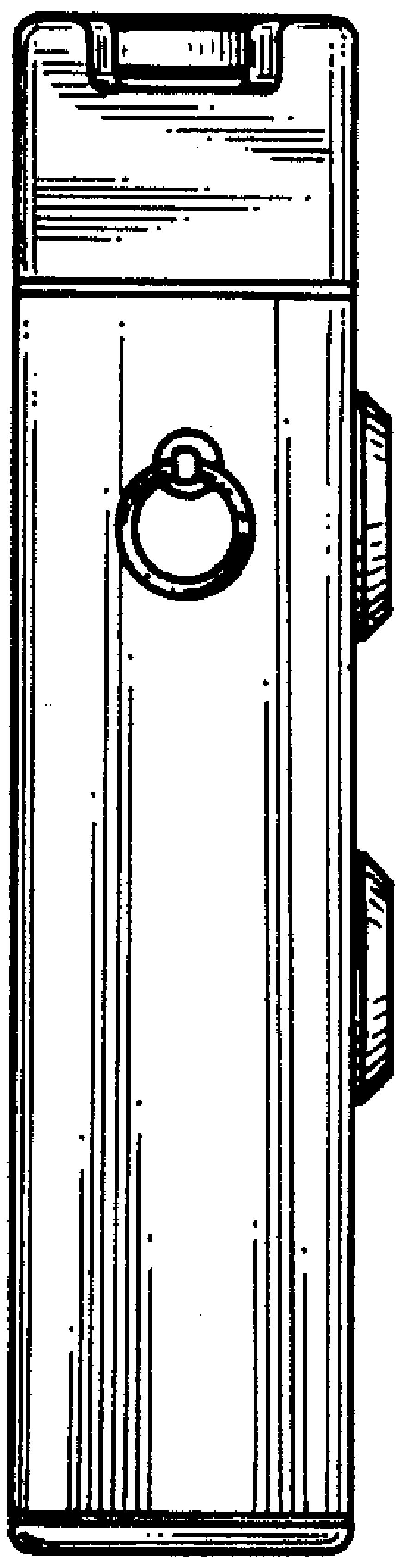

FIG. 5

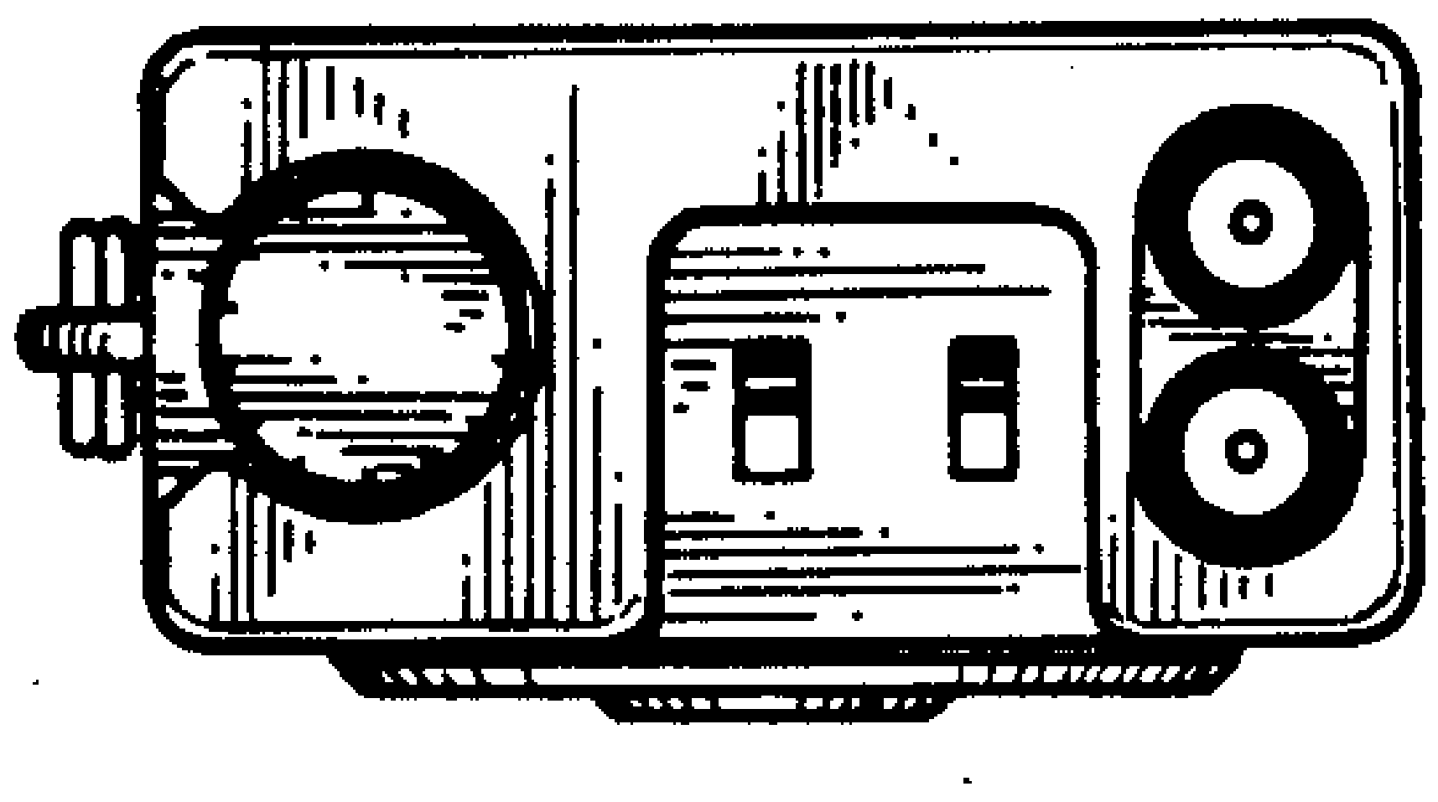

FIG. 6